

Notice of References Cited	Application/Control No. 10/083,596	Applicant(s)/Patent Under Reexamination OYAKE ET AL.	
	Examiner Martin J Angebrannndt	Art Unit 1756	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-4,609,614	09-1986	Pampalone et al.	430/323
	C	US-6,465,149	10-2002	Kamijima et al.	430/270.1
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	E	US-6,219,330	04-2001	Ahn et al.	369/275.1
	F	US-6,342,332	01-2002	Loo et al.	430/270.1
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	N	708439	04-1996	EP	Katsuda et al.	**
	O	61-153850	07-1986	Japan	Azuma	***
	P	59-180839	10-1984	Japan	Hamada et al.	***
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NON-PATENT DOCUMENTS

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	U	Jenkins et al., 'Fundamentals of Optics', (1976) pp. 655
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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